

Marco Farina was born in Luzern (Switzerland) in 1966; he is currently Full Professor in Electromagnetics at the Università Politecnica delle Marche (Italy) and Senior Member of IEEE; Prof. Farina is in the Technical Committee of the IEEE MTT-Society TC-25 " RF-Nanotechnology". He is author of the electromagnetic modeling software EM3DS, currently used by a number of institutions and companies, including NASA, Intel, Mitsubishi, and also (optionally) embedded in the National Instruments tool "Microwave Office". Dr. Farina designed and realized a hybrid STM/ Near Field Scanning Microwave Microscope, and was awarded by grants from US Army Research Laboratory and US Air Force Office of Scientific Research. His research interests include electromagnetic modeling of passive and active components/structures, scanning probe microscopy, nanotechnology and measurement techniques. He holds a patent for multimodal calibration of VNA (with Prof. A. Morini); the idea of the multimodal calibration was awarded ITI-A and ITI-B contracts by ESA; he published papers in several international interdisciplinary and physics journals such as Nature Communications, Applied Physics Letters, Nanoscale, IEEE Transactions etc. The paper "Microwave Microscopy for Nanoscale Characterization, Imaging and Patterning of Graphene" has been awarded the Best Conference Paper Award at 3M-Nano 2014 (International Conference on Manipulation, Manufacturing and Measurement on the Nanoscale, Taipei, Taiwan, November 2014).